

بسمه تعالی

تکلیف شماره ۳ درس طراحی وی ال اس آی: مدل ترانزیستور و مدار Inverter
موعود تحویل: ۲۰ آبان (یک هفته)

1. An NMOS device is plugged into the test configuration shown below in Figure 0.4. The input $V_{in} = 2V$. The current source draws a constant current of $50 \mu A$. R is a variable resistor that can assume values between $10k\Omega$ and $30 k\Omega$ (مقدارش میتونه بین ۱۰ کیلو اهم و ۳۰ کیلو اهم باشه). Transistor M1 experiences short channel effects and has following transistor parameters: $k' = 120 \cdot 10^{-6} V/A^2$, $V_T = 0.3$, and $V_{DSAT} = 0.6V$. The transistor has a $W/L = 2.5\mu/0.25\mu$. For simplicity body effect (یعنی رابطه ولتاژ بدنه و ولتاژ آستانه) and channel length modulation can be neglected. i.e $\lambda=0$, $\gamma=0$.

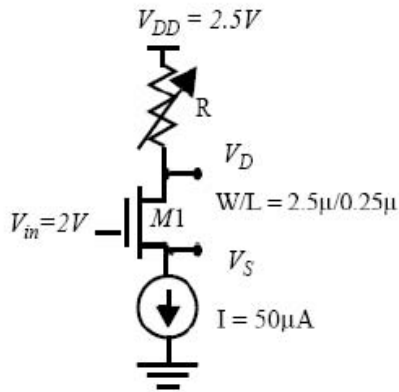


Figure 0.4 Test configuration for the NMOS device.

a. When $R = 10k\Omega$ find the operation region, V_D and V_S .

(یعنی در کدامیک از ناحیه هایی که در اسلاید ۱۵ سری 04_rabaey_ch3devices.ppt آمده بود کار میکنند؟ بعضی وقتها لازم است که حدس بزنید در کدام منطقه کار میکنند. اگر جواب معادلات درست در آمد که هیچ، اگر نه، فرض شما برای ناحیه عملکرد ترانزیستور اشتباه بوده است.)

b. When $R = 30k\Omega$ again determine the operation region V_D , V_S .

c. For the case of $R = 10k\Omega$, would V_S increase or decrease if $\lambda \neq 0$. Explain qualitatively.

2. Another equation, which models the velocity-saturated drain current of an MOS transistor is given by

(دقت کنید که این یک مدل دیگر برای ترانزیستور است و در این مساله قرار است مقدار مقاومت R_S را به دست بیاوریم که همان جریانی که مدل سابق ما میداد را به دست آوریم. یعنی این مدل و مدلی که در اسلاید ۱۴ سری 04_rabaey_ch3devices.ppt آمده بود را معادل کنیم)

$$I_{dsat} = \frac{1}{1 + (V_{GS} - V_T)/(E_{sat}L)} \left(\frac{\mu_0 C_{ox}}{2} \right) \frac{W}{L} (V_{GS} - V_T)^2$$

Using this equation it is possible to see that velocity saturation can be modeled by a MOS device with a source-degeneration resistor (see Figure 0.11).

a. Find the value of R_S such that $I_{DSAT}(V_{GS}, V_{DS})$ for the composite transistor in the figure matches the above velocity-saturated drain current equation. Hint: the voltage drop across R_S is typically

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small. Channel length modulation can be ignored (i.e., $\lambda=0$).

b. Given $E_{\text{sat}} = 1.5 \text{ V}/\mu\text{m}$ and $k' = \mu_0 C_{\text{ox}} = 20 \mu\text{A}/\text{V}^2$, what value of R_S is required to model velocity saturation. How does this value depend on W and L ?

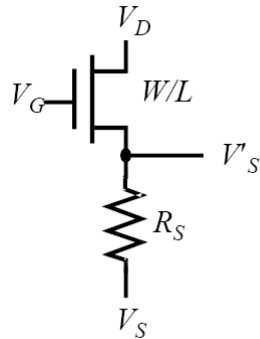
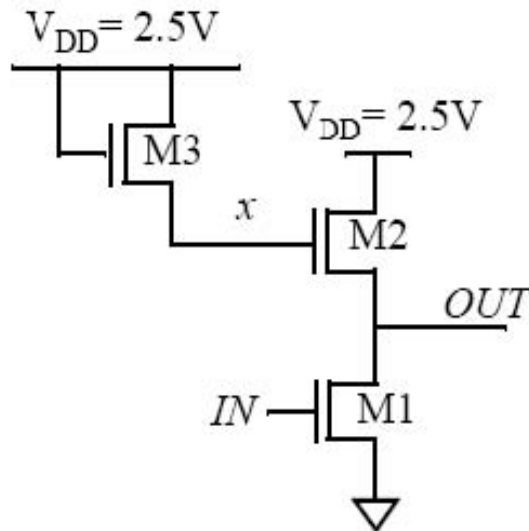


Figure 0.11 Source-degeneration model of velocity saturation.

3. Consider the following NMOS inverter. Assume that the bulk (بدنه) terminals of all NMOS device are connected to GND. Assume that the input IN has a 0V to 2.5V swing and there is no leakage current. $V_{T0}=0.43$, $\Phi_F=0.3$.



- Set up the equation(s) to compute the voltage on node x . Assume the body effect coefficient $\gamma=0.5 [\sqrt{V}]$.
- What are the modes of operation of device M_2 ? Assume $\gamma=0$.
- What is the value on the output node OUT for the case when $IN=0\text{V}$? Assume $\gamma=0$.
- Assuming devices are in velocity saturation region, $V_{\text{DSAT}} = 0.63\text{V}$ and $\gamma=0$, derive an expression for the switching threshold (V_M) of the inverter. Recall that the switching threshold is the point where $V_{IN} = V_{OUT}$. Assume that the device sizes for M_1 , M_2 and M_3 are $(W/L)_1$, $(W/L)_2$, and $(W/L)_3$ respectively. What are the limits on the switching threshold?

For this, consider two cases:

- $(W/L)_1 \gg (W/L)_2$
- $(W/L)_2 \gg (W/L)_1$

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4. [chap. 5] Sizing a chain of inverters.

a. In order to drive a large capacitance ($C_L = 25 \text{ pF}$) from a minimum size gate (with input capacitance $C_i = 10 \text{ fF}$), you decide to introduce a two-staged buffer as shown in Figure 5.12. Assume that the propagation delay of a minimum size inverter is 70 ps . Also assume that the input capacitance of a gate is proportional to its size. Determine the sizing of the two additional buffer stages that will minimize the propagation delay. Assume the junction capacitance to gate capacitance ratio $\gamma=1$.

b. If you could add any number of stages to achieve the minimum delay, how many stages would you insert? What is the propagation delay in this case?

c. Describe the advantages and disadvantages of the methods shown in (a) and (b).

d. Determine a closed form expression for the power consumption in the circuit. Consider both the gate and junction capacitances in your analysis. What is the power consumption for a supply voltage of 2.5 V , an activity factor of 1, and a clock period of T ?

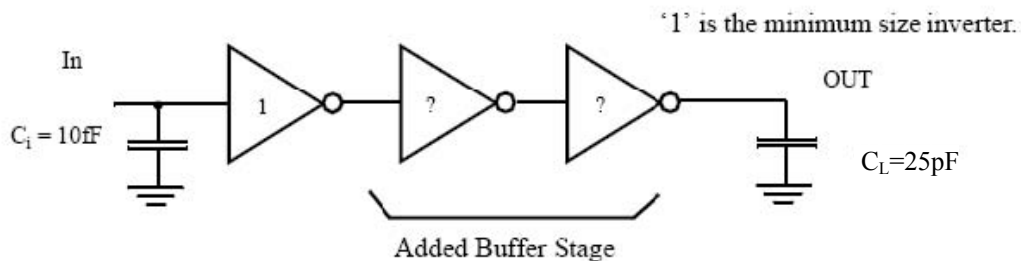


Figure 5.12 Buffer insertion for driving large loads.